RENESAS

HD74CDC2510B

3.3-V Phase-lock Loop Clock Driver

REJ03D0826-0900 (Previous: ADE-205-219G) Rev.9.00 Apr 07, 2006

Description

The HD74CDC2510B is a high-performance, low-skew, low-jitter, phase-lock loop clock driver. It uses a phase-lock loop (PLL) to precisely align, in both frequency and phase, the feedback (FBOUT) output to the clock (CLK) input signal. It is specifically designed for use with synchronous DRAMs. The HD74CDC2510B operates at 3.3 V V_{CC} and is designed to drive up to five clock loads per output.

Bank of outputs provide ten low-skew, low-jitter copies of the input clock. Output signal duty cycles are adjusted to 50 percent independent of the duty cycle at the input clock. Bank of outputs can be enabled or disabled via the control (G) inputs. When the G inputs are high, the outputs switch in phase and frequency with CLK; when the G inputs are low, the outputs are disabled to the logic-low state.

Unlike many products containing PLLs, the HD74CDC2510B does not require external RC networks. The loop filter for the PLL is included on-chip, minimizing component count, board space, and cost.

Because it is based on PLL circuitry, HD74CDC2510B requires a stabilization time to achieve phase lock of the feedback signal to the reference signal. This stabilization time is required, following power up and application of a fixed-frequency, fixed-phase signal at CLK, as well as following any changes to the PLL reference or feedback signals. The PLL can be bypassed for test purposes by strapping AV_{CC} to ground.

Features

- Meets "PC SDRAM registered DIMM design support document, Rev. 1.2"
- Phase-lock loop clock distribution for synchronous DRAM applications
- External feedback (FBIN) pin is used to synchronize the outputs to the clock input
- No external RC network required
- Support spread spectrum clock (SSC) synthesizers
- Ordering Information

| Part Name | Package Type | Package Code (Previous code) | Package Abbreviation | Taping Abbreviation (Quantity) |
|-----------------|--------------|---------------------------------|-------------------------|-----------------------------------|
| HD74CDC2510BTEL | TSSOP-24 pin | PTSP0024JB-A | Т | EL (1,000 pcs / Reel) |
| | | (TTP-24DBV) | | |

*Only by a change of a suffix (A to B) for standardization, there isn't any change of the product.

Function Table

| Inp | uts | Outputs | | | |
|-----|-----|----------|-------|--|--|
| G | CLK | 1Y (0:9) | FBOUT | | |
| X | L | L | L | | |
| L | Н | L | Н | | |
| Н | Н | Н | Н | | |

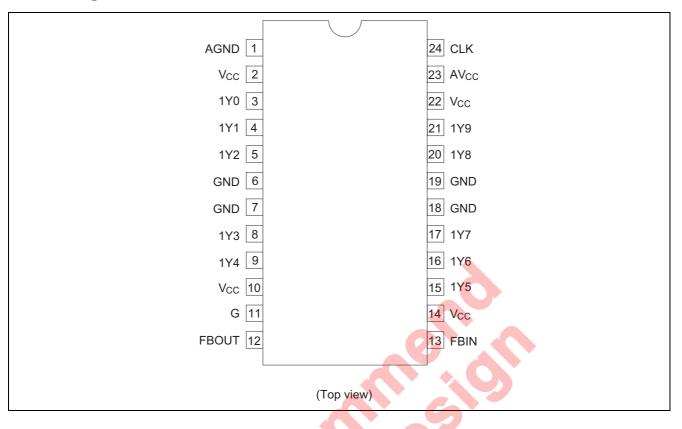
H: High level

L: Low level

X: Immaterial



Pin Arrangement



Absolute Maximum Ratings

| Symbol | Ratings | Unit | Conditions |
|-------------------------------------|--|--|--|
| V _{cc} | -0.5 to 4.6 | V | |
| V | -0.5 to 6.5 | V | |
| Vo | –0.5 to V _{CC} +0.5 | V | |
| I _{IK} | _50 | mA | V ₁ < 0 |
| I _{OK} | ±50 | mA | $V_{\rm O}$ < 0 or $V_{\rm O}$ > $V_{\rm CC}$ |
| lo | ±50 | mA | $V_{\rm O}$ = 0 to $V_{\rm CC}$ |
| I _{CC} or I _{GND} | ±100 | mA | |
| Ρτ | 0.7 | W | |
| | | | |
| T _{stg} | –65 to +150 | °C | |
| | V _{CC} V _I V _O I _{IK} I _{OK} I _O I _{CC} or I _{GND} Рт | $\begin{array}{c c c c c c c c c c c c c c c c c c c $ | $\begin{array}{c c c c c c c c c c c c c c c c c c c $ |

Notes: Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.

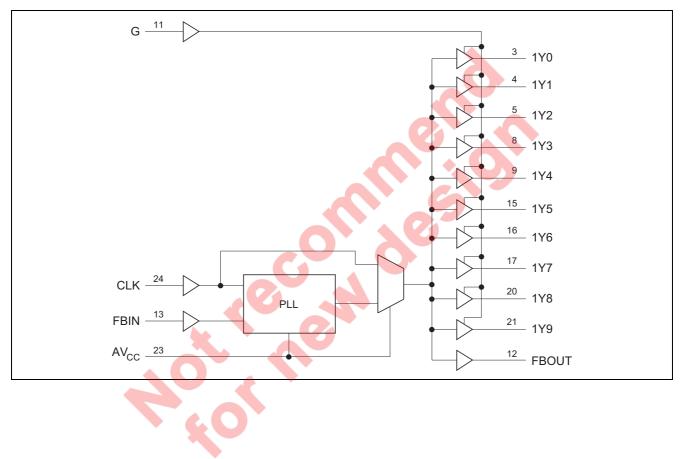
- 1. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.
- 2. This value is limited to 4.6 V maximum.
- 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.



| ltem | Symbol | Min | Тур | Max | Unit | Conditions |
|-----------------------|-----------------|-----|-----|-----------------|------|------------|
| Supply voltage | V _{cc} | 3.0 | — | 3.6 | V | |
| Input voltage | VIH | 2.0 | — | — | V | |
| | VIL | _ | — | 0.8 | | |
| | VI | 0 | — | V _{CC} | | |
| Output current | I _{OH} | — | — | -12 | mA | |
| | I _{OL} | _ | — | 12 | | |
| Operating temperature | Ta | 0 | | 85 | °C | |

Note: Unused inputs must be held high or low to prevent them from floating.

Logic Diagram





Pin Function

| Pin name | No. | Туре | Description |
|------------------|---|--------|--|
| CLK | 24 | 1 | Clock input. CLK provides the clock signal to be distributed by the HD74CDC2510B clock driver. CLK is used to provide the reference signal to the integrated PLL that generates the clock output signals. CLK must have a fixed frequency and fixed phase for the PLL to obtain phase lock. Once the circuit is powered up and a valid CLK signal is applied, a stabilization time is required for the PLL to phase lock the feedback signal to its reference signal. |
| FBIN | 13 | I | Feedback input. FBIN provides the feedback signal to the internal PLL. FBIN must be hard-wired to FBOUT to complete the PLL. The integrated PLL synchronizes CLK and FBIN so that there is nominally zero phase error between CLK and FBIN. |
| G | 11 | I | Output bank enable. G is the output enable for outputs 1Y(0:9). When G is low, outputs 1Y(0:9) are disabled to a logic-low state. When G is high, all outputs 1Y(0:9) are enabled and switch at the same frequency as CLK. |
| FBOUT | 12 | 0 | Feedback output. FBOUT is dedicated for external feedback. It switches at the same frequency as CLK. When externally wired to FBIN, FBOUT completes the feedback loop of the PLL. |
| 1Y(0:9) | 3, 4, 5, 8, 9, 15, 16, 17, 20, 21 | 0 | Clock outputs. These outputs provide low-skew copies of CLK. Output bank 1Y(0:9) is enabled via the G input. These outputs can be disabled to a logic low state by deasserting the G control input. |
| AV _{CC} | 23 | Power | Analog power supply. AV_{CC} provides the power reference for the analog circuitry. In addition, AV_{CC} can be used to bypass the PLL for test purposes. When AV_{CC} is strapped to ground, PLL is bypassed and CLK is buffered directly to the device outputs. |
| AGND | 1 | Ground | Analog ground. AGND provides the ground reference for the analog circuitry. |
| V _{CC} | 2, 10, 14, 22 | Power | Power supply |
| GND | 6, 7, 18,19 | Ground | Ground |

Electrical Characteristics

| Item | Symbol | Min | Typ ^{*1} | Max | Unit | Test Conditions |
|--------------------------|-----------------|----------------------|-------------------|------|------|--|
| Input clamp voltage | VIK | | | -1.2 | V | $V_{CC} = 3 V, I_1 = -18 mA$ |
| Output voltage | V _{OH} | V _{cc} -0.2 | — | _ | V | V_{CC} = Min to Max, I_{OH} = -100 μ A |
| | | 2.1 | _ | _ | | $V_{CC} = 3 V, I_{OH} = -12 mA$ |
| | | 2.4 | _ | _ | | V _{CC} = 3 V, I _{OH} = –6 mA |
| | V _{OL} | | _ | 0.2 | | V_{CC} = Min to Max, I_{OL} = 100 μ A |
| | | — | _ | 0.8 | | $V_{CC} = 3 V, I_{OL} = 12 mA$ |
| | | — | _ | 0.55 | | $V_{CC} = 3 V, I_{OL} = 6 mA$ |
| Input current | I _{IN} | — | — | ±5 | μA | V_{CC} = 3.6 V, V_{IN} = V_{CC} or GND |
| Quiescent supply current | I _{CC} | _ | _ | 10 | μA | $AV_{CC} = GND, V_{CC} = 3.6 V,$ |
| | | | | | | $V_1 = V_{CC}$ or GND, $I_0 = 0$ |
| | ΔI_{CC} | — | - | 500 | μA | AV_{CC} = GND, V_{CC} = 3.3 to 3.6 V |
| | | | | | | One input at V _{CC} –0.6 V, |
| | | | | | | Other inputs at V_{CC} or GND |
| Input capacitance | C _{IN} | _ | 4 | _ | pF | V_{CC} = 3.3 V, V_{I} = V_{CC} or GND |
| Output capacitance | Co | _ | 6 | _ | pF | V_{CC} = 3.3 V, V_{O} = V_{CC} or GND |

Note: 1. For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions.

Switching Characteristics

 $(C_L = 30 \text{ pF}, \text{Ta} = 0 \text{ to } 85^{\circ}\text{C})$

| Item | Symbol | Vcc | = 3.3 V±0 | .3 V | Unit | From (Input) | To (Output) |
|---|---------------------|------|-----------|------|-------------------|---|------------------|
| nem | Symbol | Min | Тур | Max | Unit | | |
| Phase error time | t _{pe} | -150 | | 150 | ps | 66 MHz < CLKIN↑ ≤ 100 MHz | FBIN↑ |
| Between output pins skew *1 | t _{sk (O)} | _ | _ | 200 | ps | Any Y or FBOUT, F (clkin = 100 MHz) | Any Y or FBOUT |
| Cycle to cycle jitter | | -100 | — | 100 | ps | F (clkin = 100 MHz) | Any Y or FBOUT |
| Duty cycle | | 45 | _ | 55 | % | F (clkin = 100 MHz) | Any Y or FBOUT |
| Output rise / fall time | t_{TLH} | 5.0 | _ | 1.0 | volts/ns | | Any Y or FBOUT |
| | t_{THL} | 5.0 | _ | 1.0 | | | Any Y or FBOUT |
| Analog power supply rejection (DC to 10 MHz) | Vapsr *2 | 100 | — | _ | mV _{P-P} | 0 | AV _{CC} |

Notes: The specifications for parameters in this table are applicable only after any appropriate stabilization time has elapsed.

1. The $t_{sk(O)}$ specification is only valid for equal loading of all outputs.

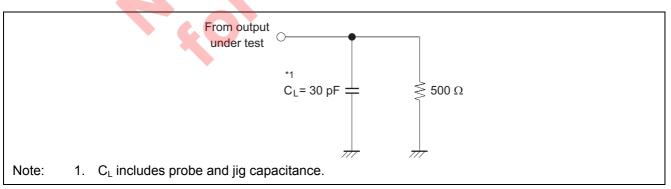
2. This parameter is characterized but not tested.

Timing Requirements

| Item | Symbol | Min | Max | Unit | Test Conditions |
|----------------------------------|--------------------|-----|-----|------|-----------------|
| Input clock frequency | f _{clock} | 50 | 125 | MHz | |
| Input clock duty cycle | | 40 | 60 | % | |
| Stabilization time ^{*1} | | | 1 | ms | After power up |

Note: 1. Time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal. In order for phase lock to be obtained, a fixed-frequency, fixed-phase reference signal must be present at CLK. Until phase lock is obtained, the specifications for propagation delay and skew parameters given in the switching characteristics table are not applicable.

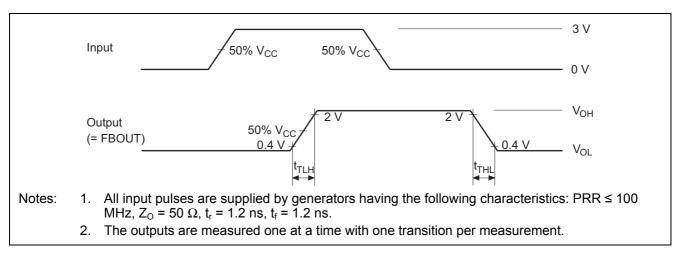
Test Circuit



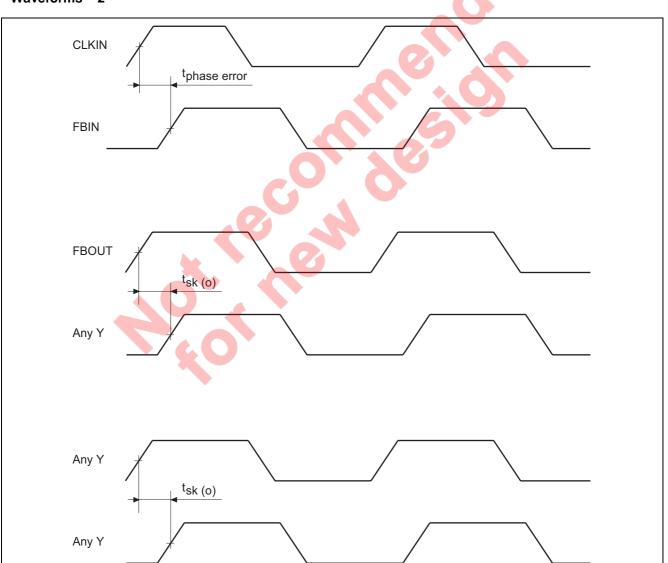


HD74CDC2510B

Waveforms - 1

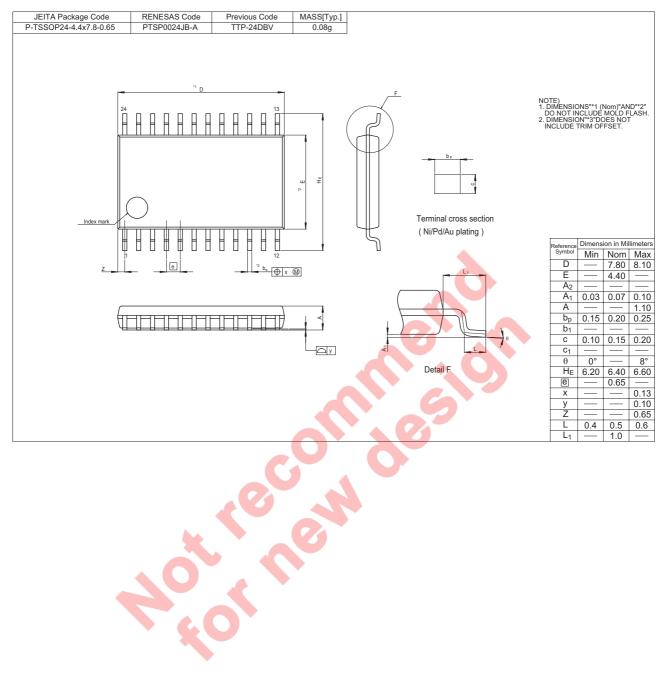








Package Dimensions





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